Dual Probes

Giga Test Labs
Serving the Electronics Industry with Engineering Excellence

Dual Probes

GTL Microwave Probes were developed to provide superior electrical performance and unparalleled durability when used for probing on wafer, package, BGA, PCB, socket, backplane, high density interconnect, etc. The ruggedized probe tips extend the life of the probes.

Electrical Characteristics:
- 50 Ohm Impedance
- DC to 40 GHz Frequency Range
- -15 dB Return Loss
- 1.5 dB Insertion Loss

Mechanical Characteristics:
- Probe Tip Configurations: GSSG
- 2.92 mm connector that is mechanically compatible with:
  - SMA Cables
  - 3.5 mm Cables
  - 2.92 mm Cables
- Maximum Connector Torque: 10 inch-lbs
- Gold Plated Probe Tips
- Standard Pitches: 200µ, 250µ, 300µ, 450µ, 500µ, 600µ, 750µ, 1000µ
- Custom Pitches Available
- Signal to Signal Pitch is adjustable from 200µ - 1500µ

GTL40-750-GSSG-DX S/N 1290 GS
LOG MAG | Insertion Loss dB | 1 dB/DIV

GTL40-750-GSSG-DX S/N 1290 GS
LOG MAG | Return Loss dB | 10 dB/DIV

Phone: (408)524-2700
Website: Gigatest.com
Dual Probe Mechanical Outline

- 2.92 mm female 40 GHz connectors
- Signal to signal locking screw
- Signal to signal adjustment screw
- PROBE TIP CONFIGURATION

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